

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Component

IECQ Certificate No.: IECQ-C ULTW 20.0001
CB Certificate No.: 50600349 AQP

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Approval Scope

Table 1 Resistance Range & Electrical Characteristics

Туре	T.C.R (PPM/℃)	Max. Working Voltage	Max. Over- Ioad Voltage	Operating Temperature (Temp. Range)(℃)		Insulation Resistance	Power Rating	Resistance Range(Ω)		
				Min.	Max.		at 70℃	F(±1%)	G(±2%)	J(±5%)
RLM12	±50	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1/4W	10mΩ-50mΩ	10mΩ-50mΩ	10mΩ-50mΩ
						over 100MΩ	1/2W	10mΩ-50mΩ	10mΩ-50mΩ	10mΩ-50mΩ
						over 100MΩ	1W	10mΩ-50mΩ	10mΩ-50mΩ	10mΩ-50mΩ
RLM20	±50	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1/2W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	3/4W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	1W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	3/2W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
RLM25	±50	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1W	2mΩ~50mΩ	2mΩ~50mΩ	2mΩ~50mΩ
						over 100MΩ	3/2W	2mΩ~15mΩ	2mΩ~15mΩ	2mΩ~15mΩ
						over 100MΩ	2W	2mΩ~10mΩ	2mΩ~10mΩ	2mΩ~10mΩ
	±275	(P*R) ^{1/2}	5 X rated power for 5 sec	-55	170	over 100MΩ	1W	1mΩ	1mΩ	1mΩ
						over 100MΩ	3/2W	1mΩ	1mΩ	1mΩ
						over 100MΩ	2W	1mΩ	1mΩ	1mΩ

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		Table 2	Part Numl		
RLM 12 Item Series No.	<u>F</u> Resistance tolerance	<u>T</u> Packaging	<u>S</u> Power Rating	<u>M</u> Metal	R010 Resistance
12:1206 (3216)	F:±1% G:±2% J:±5%	T: Paper	A=1/4W S=1/2W C=1W	M=Metal	e.g: R010=10m Ω R050=50m Ω
RLM 20 Item Series No.	<u>F</u> Resistance tolerance	<u>E</u> Packaging	<u>C</u> Power Rating	R020 Resistance	
20:2010 (5025)	F:±1% G:±2% J: ±5%	E:Embossed tape	S=1/2W I=3/4W C=1W D=3/2W	e.g : R003=3m Ω R050=50m Ω	
RLM 25 Item Series No.	<u>F</u> Resistance tolerance	<u>E</u> Packaging	<u>C</u> Power Rating	R020 Resistance	
25:2512 (6432)	F:±1% G:±2% J: ±5%	E:Embossed tape	C=1W D=3/2W E=2W	e.g : R001=1m Ω R050=50m Ω	

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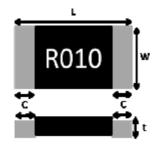
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1.2 Outline Drawing and Dimension

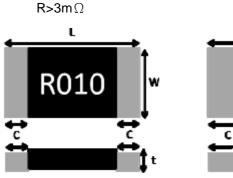
The outline drawing and dimension is listed as Table 3.

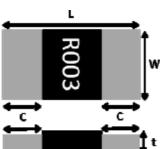
Table 3 Outline Drawing and Dimension

RLM12



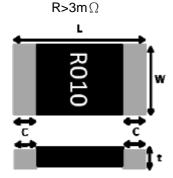
RLM20

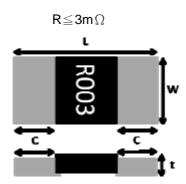




 $R \leq 3m\Omega$

RLM25





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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

IECQ-C Schedule of Scope Rev. 01



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					unit:mm
Style	L	W	С	t	Material
RLM12	3.2±0.2	1.6±0.2	0.5 ± 0.3	0.6 ± 0.2	
DLM20	5.0±0.2	2.5±0.2	1.5±0.3(R≦3mΩ)	0.6 ±0.2	Metal: Alloy Over Coating:molding Compound UL-94V grade
RLM20			0.6±0.3(R>3mΩ)	0.0 10.2	
RLM25	6.4±0.2	3.2±0.2	2.0±0.2(R≦3mΩ)	0.6 ±0.2	
			0.9±0.2(R>3mΩ)		

1.3 Related Documents

IECQ 03-1, Rule of Procedure - Part 1: General Requirements for all IECQ Schemes

IECQ 03-3, Rule of Procedure – Part 3: IECQ Approved Component Products, Related Materials & Assemblies Scheme

IECQ 03-3-2: Rule of Procedure – Part 3-2: IECQ Approved Component Products, Related Materials & Assemblies Scheme, IECQ Approved Component – Automotive Qualification Program (IECQ AC-AQP)

AEC-Q200 REV D, Stress Test Qualification for Passive Components

AEC-Q200-004A Resistance Measurement Method

AEC-Q200-002B Human Body Model Electrostatic Discharge Test

AEC-Q200-005A Board Flex Test

AEC-Q200-006A Terminal Strength (SMD)/Shear Stress Test

JEDEC JESD22-A104D Temperature Cycling

JEDEC JEP 140 Beaded Thermocouple Temperature Measurement of Semiconductor Package

JEDEC JEP 153A Characterization and Monitoring Thermal Stress Test Oven Temperatures

MIL-STD-883K Method 2009 Test methods standard microcircuits

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JEDEC JESD22-B100B Physical Dimensions

MIL-STD-202H, Test Method Standard, Electronic and Electrical Component Part

EIA/IPC/JEDEC J-STD-002D, Solderability Tests for Component Leads, Terminations, Lugs, Terminals and Wires

ASTM-B-809-95(2013): Standard Test Method for Porosity in Metallic Coatings by Humid Sulfur Vapor ("Flowers-of-Sulfur")

IEC 60115-1 Edition 4.0: Fixed Resistors for Use in Electronic Equipment - Part 1: Generic Specification

UL-94: Flammability

